行政院國家科學委員會專題研究計畫 成果報告

針對 3D 整合之電子設計自動化技術開發--子計畫三：針對三維規則型邏輯結構之架構探索及穩健合成系統開發(2/2)
研究成果報告(完整版)

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公 開 資 訊 ： 本計畫可公開查詢

中 華 民 國 100 年 10 月 31 日

中文摘要：

隨著製程的進步，導線延遲取代了元件的延遲，逐漸主宰著系統的效率，並且在設計上成為一個非常關鍵的因素。三維電路架構在垂直方向的可行性提供了電路設計更多的彈性，當然也同時提高了設計和分析的複雜度。但無可否認的，三維電路架構在電路設計的領域開啟了新的風貌。不論是從理論分析的角度或是實驗的角度，三維電路在 VLSI 電路設計上，於導線長度的緊縮(wire length reduction)、功率消耗的減少(power reduction)、晶片面積的減少(chip area reduction)及電路元件密度上升(increased device density)等各項指標都有顯著的改善。然而，導線的延遲很難在早期的系統設計中預知，必須要等到佈局完成才可以有初步的分析。因此，在本計劃中，我們會先探討導線延遲所造成的潛在因素是如何影響系統的效能，並且重新評估一些具有同成果品質(Quality of Result) 目標的舊有佈局方法，並在往後的階段中，利用其特性推廣至三維規則型邏輯架構探索中。

三維規則型邏輯架構之推廣與應用所面臨的眾多挑戰之一是缺乏量身訂做的設計自動化工具(design automation tools)。本計劃將針對三維規則型邏輯結構(3D regular logic structure)發展相對應之自動化設計演算法，並利用這些新開發的工具來進行三維規則型邏輯結構之架構探索(architecture exploration)，以期在硬體資源的使用與系統效能之間取得最佳平衡。

英文摘要：

The wire delay is gradually dominating the system performance and becoming one of the most critical design issues. Three-dimensional integrated circuit (3D IC) technologies enable to stack multiple dies on a single chip and provide several unique advantages compared to conventional 2D approaches such as wire length reduction, power reduction, chip area reduction, and increasing device density. However, it is hard to precisely estimate the wire delay in early design stages until floorplan/placement is actually done. In this project, we first show how the latency incurred by wire delay dominates system throughput and re-evaluate several exiting floorplanning strategies which are considered providing the same quality of result (QoR) in the past. Then we propose new throughput-aware floorplanning/placement strategies which dynamically optimizes a set of most critical performance cycles in the system. These methodologies will be extended into the architecture exploration in 3D regular structures.

One of the tough challenges for the broad applications of 3D regular structure is the lack of Electronic Design Automation (EDA) tools. In this project, we intend to develop the advanced algorithms targeting 3D regular logic structures. Furthermore, by utilizing the newly developed dedicated algorithms, we can explore more advanced architectures for 3D logic structures to achieve the perfect balance among hardware utilization, fault-tolerance capability and

system performance.

行政院國家科學委員會補助專題研究計畫■ 成 果 報 告
□期中進度報告

針對三維規則型邏輯結構之架構探索及穩健合成系統開發

(2/2)

計畫類別：□ 個別型計畫　　■ 整合型計畫
計畫編號：NSC 99－ 2220 － E － 009 － 037 －
執行期間： 99 年 8 月 1 日至 100 年 7 月 31 日

計畫主持人：黃俊達 副教授 國立交通大學電子系
共同主持人：
計畫參與人員：劉家宏、陳詣航、陳嘉怡、劉揚翔、劉廣正、許晉維、陳怡廷、謝明廷、賴鵬先、林惠珊

成果報告類型(依經費核定清單規定繳交)：□精簡報告　■完整報告

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執行單位：

中　華　民　國　　100 年　　10 月 30 日

針對三維規則型邏輯結構之架構探索及穩健合成系統開發 (2/2)

計劃編號：NSC99－2220－E－009－037－ 執行期間：98 年 8 月 1 日至 100 年 7 月 31 日

主持人：黃俊達 副教授 國立交通大學電子所

一、 摘要

中文摘要

隨著製程的進步，導線延遲取代了元件的延遲，逐漸主宰著系統的效率，並且在設計上成為一個非常關鍵的因素。三維電路架構在垂直方向的可行性提供了電路設計更多的彈性，當然也同時提高了設計和分析的複雜度。但無可否認的，三維電路架構在電路設計的領域開啟了新的風貌。不論是從理論分析的角度或是實驗的角度，三維電路在 VLSI 電路設計上，於導線長度的緊縮(wire length reduction)、功率消耗的減少(power reduction)、晶片面積的減少(chip area reduction)及電路元件密度上升(increased device density)等各項指標都有顯著的改善。然而，導線的延遲很難在早期的系統設計中預知，必須要等到佈局完成才可以有初步的分析。因此，在本計劃中，我們會先探討導線延遲所造成的潛在因素是如何影響系統的效能，並且重新評估一些具有同成果品質(Quality of Result) 目標的舊有佈局方法，並在往後的階段中，利用其特性推廣至三維規則型邏輯架構探索中。

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關鍵字

規則型邏輯結構、架構探索、產能最佳化、多時脈溝通、高階合成、設計方法論、設計自動化。

Abstract

The wire delay is gradually dominating the system performance and becoming one of the most critical design issues. Three-dimensional integrated circuit (3D IC) technologies enable to stack multiple dies on a single chip and provide several unique advantages compared to conventional 2D approaches such as wire length reduction, power reduction, chip area reduction, and increasing device density. However, it is hard to precisely estimate the wire delay in early design stages until floorplan/placement is actually done. In this project, we first show how the latency incurred by wire delay dominates system throughput and re-evaluate several exiting floorplanning strategies which are considered providing the same quality of result (QoR) in the past. Then we propose new throughput-aware floorplanning/placement strategies which dynamically optimizes a set of most critical performance cycles in the system. These methodologies will be extended into the architecture exploration in 3D regular structures.

One of the tough challenges for the broad applications of 3D regular structure is the lack of Electronic Design Automation (EDA) tools. In this project, we intend to develop the advanced algorithms targeting 3D regular logic structures. Furthermore, by utilizing the newly developed dedicated algorithms, we can explore more advanced architectures for 3D logic structures to achieve the perfect balance among hardware utilization, fault-tolerance capability and system performance.

Keyword

Regular logic architecture, architecture exploration, throughput optimization, multicycle communication, high-level synthesis, design methodology, and design automation.

二、 計劃緣由及目的

Introduction

With the advance of semiconductor manufacturing process technology, ever-shrinking feature size and exponentially growing number of transistors on a single die are raising numerous tough challenges such as signal integrity, power integrity and dissipation, leakage power, clock distribution and yield issues [1]. In addition, the global interconnect delay fails to scale as the device delay does and is gradually dominating the system performance [1]. Therefore, a solution that can both alleviate the global interconnect delay bottleneck as well as provide new avenues to enable even advanced device and architecture innovations is eagerly demanded. While approaching the physical limitations, traditional scaling is no longer the best way for advancing manufacturing process technology, and hence three-dimensional (3D) technologies have been emerging in recent years [2]–[5]. 3D integrated circuit technologies enable stacking multiple dies on a single chip [6][7] and provide several unique advantages compared to those conventional two-dimensional (2D) ones, such as higher system integration, better heterogeneous integration

capability, and shorter global wirelength (i.e., better performance).

However, stacking chips or dies is not a whole new idea. SiPs (system-in-package) and PoPs (package-on-package), which have been available in industry for several years, can also be regarded as 3D techniques in the broad sense [8]–[10]. SiPs and PoPs stack multiple chips and use wire-bonding for vertical signal links while packaging. However, the locations for wire-bonding are restricted on the periphery of a chip layer and the package substrate. Thus these kinds of 3D techniques are facing the problems such as limited number of pins for vertical connections, long and slow vertical signal paths, and chip-package codesign. Among those

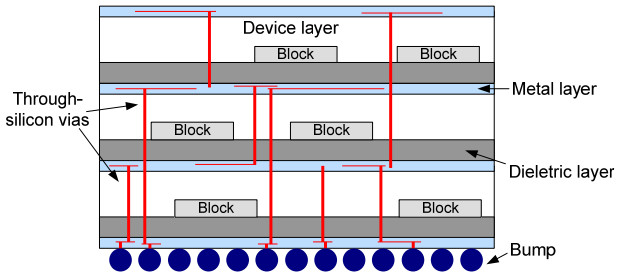


Figure 1. A TSV-based 3D structure.

state-of-the-art 3D integration technologies, through-silicon via (TSV) is one of the most promising methods to accomplish vertical interconnects between different layers [4]. Fig. 1 illustrates a typical TSV-based 3D IC structure. By utilizing the wafer/die bonding techniques, TSVs cut across thinned silicon substrates to make inter-die connections, which results in high compatibility with the present typical CMOS processes. All external I/O signals must pass through those metal bumps located at the bottom of the 3D structure to bridge the internal logic and the external system [11]–[13].

Observation and Motivation

Compared with a typical 2D design, though a TSV-based 3D design can generally reduce the global interconnect delay, currently available TSV fabrication processes still suffer from relatively low yield as well as large TSV pitch size [14]. It is reported that in 22*nm* technology a TSV with 8μm pitch occupies roughly the same area as 1k SRAM cells (0.061μm^2) [1], and TSV yield drops to about 80% in a 3D design with 2k TSVs [15]. Therefore, using less number of TSVs to complete a 3D design is highly desirable in terms of both yield and area cost. As a consequence, the issue of TSV minimization must be properly addressed in a design flow as stepping into the 3D IC era.

In general, 3D IC backend flows can be roughly classified into two categories. The first one is to combine TSV minimization into later design processes such as floorplanning [16] and placement [17][18], which aims at both objectives at the same time. However, the above mix-in-one problem is likely to become too complicated to be well handled. Alternatively, the authors in [19]–[21] all suggest that it is crucial to make 3D partitioning an independent stage in the backend flow as shown in Fig. 2. The suggested flow first partitions a given design into different layers and then solves the remaining problem by classical 2D techniques or their simple extensions. Hence, this methodology efficiently reduces the problem complexity while keeping the quality of results nearly at the same level [19][20]. Since the outcome of 3D partitioning mainly determines the number of required TSVs, several previous studies have been proposed to

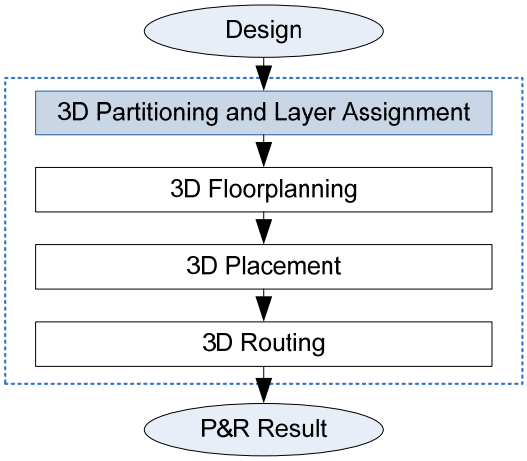


Figure 2. Referenced backend flow for 3D ICs.

tackle the problem of 3D partitioning for TSV minimization. One solution is to solve the problem using integer linear programming (ILP) [22]. However, it can only solve small-size problem since its runtime grows exponentially as problem size increases. In [23][24], each of them develops a modified FM-based [25] partitioning method to obtain the resultant layer assignment. However, all these methods only focus on minimizing the total amount of TSVs or die area, and do nothing about evenly distributing TSVs among layers. Meanwhile, the authors of 3D FPGA synthesis frameworks TPR [26] and 3D MEANDER [27] alternatively use a two-step approach – first applying the well-known partitioning algorithm hMetis [28] to divide a design into a set of layer-unaware partitions, and then associating each partition with a layer (i.e., layer assignment) – to accomplish 3D design partitioning. Though hMetis is an efficient and effective multi-way min-cut partitioning tool, it lacks for the notion of layer. In general, a typical 2D partitioning algorithm basically gives a similar weight to a cut between any two partitions, whereas those weights can vary a lot in 3D partitioning and highly depend on whether two partitions (i.e., layers) are close or far away from each other.

Indeed, 3D designs can help minimize long interconnects through the extensive use of TSVs. However, utilizing too few TSVs may limit this benefit and even increase the total wirelength, while allocating too many TSVs surely enlarges design area size [14]. Though only focusing on TSV reduction cannot guarantee decrease of wirelength after placement and routing, a TSV-minimized (also area-minimized) partitioning technique should still be incorporated as a

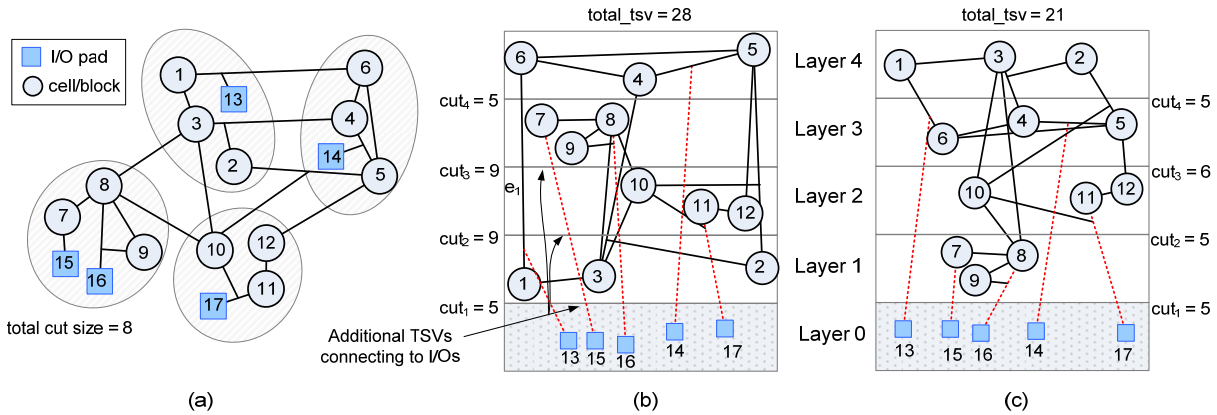


Figure 3 (a) A 4-way min-cut partitioned design, (b) the worst possible, and (c) the best possible 3D layering outcomes based on the partitioning in (a).

preprocessing stage in a 3D design flow, which provides a good starting point for further tradeoff between area and wirelength in the following stages.

Fig. 3 demonstrates a simple 4-layer 3D partitioning example. A given design with its 4-way min-cut partitioning result is presented in Fig. 3(a). Based on the same initial partitioning result given in Fig. 3(a), Fig. 3(b) and 3(c) respectively illustrate the worst possible and the best possible 3D layering outcomes in terms of the number of TSVs. From the observations on Fig. 3, here we would like to highlight two key ideas.

Firstly, all external I/O terminals must be located in the bottom-most layer. It implies those square vertices representing I/O pads must always be located in Layer 0. As a result, extra TSVs are required to properly relocate those I/O pads. As shown in Fig. 3(b), five additional signal paths (in dotted lines) suggest that 13 more TSVs are further required. Those extra signal paths are generally unconsidered in conventional multi-way min-cut partitioning algorithms. It also explains why there is a big difference between the total cut size (=8) in Fig. 3(a) and the number of total TSVs (=28) in Fig. 3(b).

Secondly, different layer assignments usually result in different TSV requirements even the given initial partitioning result is identical. For instance, given the partitioning result shown in Fig. 3(a), the total number of TSVs can range from 21 to 28 after examining all possible layer assignments. Nevertheless, the best layering result with the minimum number of TSVs shown in Fig. 6(d) cannot be derived from the initial partitioning outcome shown in Fig. 3(a), which is obtained from hMetis.

According to the aforementioned discussions, it should be evident that conventional multi-way min-cut partitioning algorithms virtually have no chances to perform 3D partitioning well in their original forms due to their unawareness about the fundamentals of vertical die-stacking structure. Therefore, a layer-aware partitioning algorithm specifically dedicated to 3D structures is strongly demanded for advanced 3D IC design methodologies.

Meanwhile, according to [1][26][29], the SB has already been the most area-consuming unit compared to the other elements in 2D FPGAs for a long time. The situation is becoming even worse in 3D FPGAs because the 3D-SB is exactly where those TSVs locate. As shown in Fig. 4, as manufacturing technology keeps scaling down, the area share of the 3D-SB is getting more dominant, which is mainly because TSVs are not scaled well. Moreover, it is found that the TSV utilization is actually quite low if the 3D-SB with full vertical connectivity is in use. As depicted

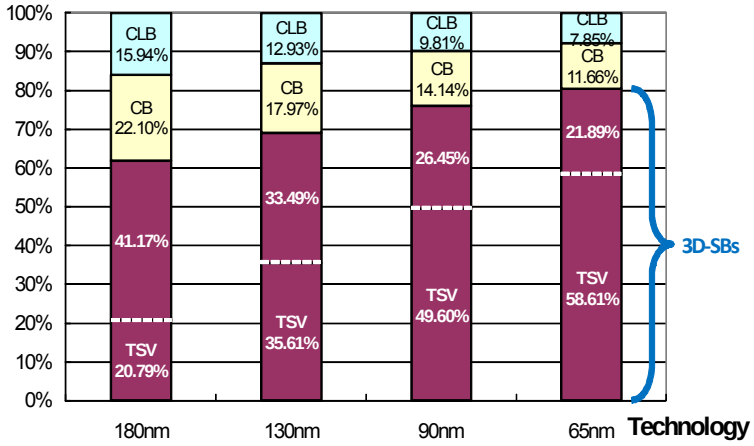


Figure 4. The area ratio for each component in a tile.

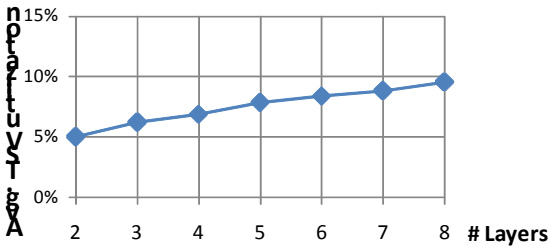


Figure 5. The average TSV utilization in a 3D FPGA architecture with full vertical connectivity.

in Fig. 5, the TSV utilization is still less than 10% even in the 8-layer 3D FPGA. Therefore, there is a strong motive to optimize the 3D-SB structure and the 3D-SB deployment strategy for area saving.

3D MEANDER is another design framework for 3D FPGAs. In addition, it also studies the impact of different deployment strategies for 3D-SBs. It proposes a family of 3D FPGA architectures in which 2D-SBs and 3D-SBs are mixed up in certain regular spatial patterns. However, the number of available TSVs within a 3D-SB is assumed fixed in 3D MEANDER. That is, it does not investigate what the impact of the different number of TSVs in a 3D-SB is.

In this project, we first point out that the utilization of TSVs is actually very low in a 3D FPGA architecture with full vertical connectivity, which inspires us to discover new architectures that can achieve a better balance between area and delay. There are basically two ways for area reduction: reducing the number of TSVs in a 3D-SB, and reducing the number of 3D-SBs. In combination of above two ideas, we propose two major families of architectures and extensively evaluate numerous instances through thorough and systematic comparisons to pick out the better ones. Note that minimizing area only is one thing, but minimizing area without sacrificing delay is completely another thing.

三、 研究方法與成果

This project indicates the design issues when integrating 3D stacking technology into regular architectures. This emerging technology allows stacking multiple layers of dies and typically resolves the vertical inter-layer connection issue by TSVs. However, TSVs also occupy significant silicon estate as well as incur reliability problems. The deployment of TSVs must be very judicious in 3D designs. An iterative layer-aware partitioning algorithm, named *iLap*, for TSV minimization in 3D structures is proposed. On the other hand, a generic 2D FPGA architecture can evolve into a 3D one by extending its signal switching scheme from 2D to 3D by means of TSVs. However, replacing all 2D switch boxes (SBs) by 3D ones with full vertical connectivity is found both area-consuming and resource-squandering. Therefore, it is possible to greatly reduce the footprint with only minor delay increase by properly tailoring the structure and deployment strategy of 3D SB. In this project, we also perform a comprehensive architectural exploration of 3D FPGAs. Various architectural alternatives are proposed and then evaluated thoroughly to pick out the most appropriate ones with a better area/delay balance.

Layer-Aware Iterative Partitioning

A. Problem formulation

A design is modeled as a hypergraph $G = (V, E)$, where V is a set of vertices including a set of functional cells (or blocks) C and a set of I/O pads I (i.e., $V = C \cup I$, $C \cap I = \varnothing$); and E is a set of hyperedges. For each vertex $v \in V$, $area(v)$ denotes the area cost of v. Each hyperedge is a subset of V, i.e., $e \subseteq V \ \forall e \in E$. A k-layer disjoint partition set of G with all the I/O terminals residing in the bottom-most layer is represented as $L = \{L_0=I, L_1, L_2 \ldots L_k\}$, where L_i is the partition assigned to the i-th layer and is a subset of C; i.e., $L_i \subseteq C \ \forall \ 1 \le i \le k$; $L_i \cap L_j = \varnothing \ \forall i \ne j$, $1 \le i, j \le k$; and $L_1 \cup L_2 \cup \ldots \cup L_k = C$.

For a vertex v, $layer(v)$ indicates which layer v actually resides in. That is, $layer(v) = i, \ \forall \ v \in L_i$. The *range pair* of a hyperedge e is defined as $rp(e) = (b, t)$ if e connects vertices from the lower b-th layer to the upper t-th layer; i.e., $\forall \ v \in e$, $b \le layer(v) \le t$. Then the number of TSVs required to complete e can be calculated as $tsv(e) = t - b$. The *layer junction* jct_i is defined as the junction between the two adjacent layers L_{i-1} and L_i, $\forall \ 1 \le i \le k$. The number of TSVs passing through jct_i is further defined as cut_i. Hence, the total number of TSVs, *total_tsv*, needed for a 3D partitioning solution L can be determined either by summing the required TSVs for all hyperedges ($\sum_{e \in E} tsv(e)$) or by summing TSVs passing through all junctions ($\sum_{i=1}^{k} cut_i$). Consider the example shown in Fig. 3(b), $rp(e_1) = (1, 4)$ and thus $tsv(e_1) = 3$. Similarly, the total number of TSVs in Fig. 3(b) is *total_tsv* = $\sum cut_i$ = 5 + 9 + 9 + 5 = 28, including 15 TSVs connecting between cells, and 13 TSVs connecting cells and I/O pads. We would like to emphasize again that classical partitioning algorithms usually have no idea about the I/O pad connection constraint and always underestimate the real TSV demand even excluding those TSVs for connecting cells and I/O pads (8 vs. 15 in the case shown in Fig. 3(a) and 3(b)) due to their layer-unawareness. Those are the major reasons why the classical min-cut-based partitioning solutions are generally not well optimized in 3D cases (shown later).

In this paper, we model the 3D partitioning problem as a layer-aware multi-way partitioning problem. Given a target 3D structure consisting of k layers stacking vertically, a design G, and the I/O pad constraint, our proposed algorithm partitions G into k sub-designs and each sub-design is explicitly associated with a vertical layer so that the total number of TSVs is minimized. That is, given $G = (V = C \cup I, E)$ with $layer(v) = 0 \ \forall \ v \in I$, our algorithm directly finds the mapping, $1 \le layer(v) \le k \ \forall \ v \in C$, such that *total_tsv* is minimizeds.

B. Proposed algorithm

Here we propose our iterative partitioning framework that gradually constructs the solution from the bottom-most layer all the way to the topmost one. Consider that all I/O pads must reside in L_0 by definition and then the number of TSVs through jct_1 (i.e., cut_1,) is always fixed to $|I|$ no matter how other cells (or L_1~L_k) get partitioned eventually. As a result, if we define G_1 by compacting all the I/O pads into a supervertex v_s and keeping all the connected hyperedges unchanged as shown in Fig. 6(a), it is evident that jct_1 and cut_1 should still remain unchanged in G_1. Next, an arbitrary conventional k-way area-balanced min-cut partitioning algorithm is applied on G_1 to get k partitions, where $area(v_s)$ is set to zero to avoid disturbing area balancing during partitioning. Among those k disjoint partitions, exactly one partition p_s can contain v_s, which

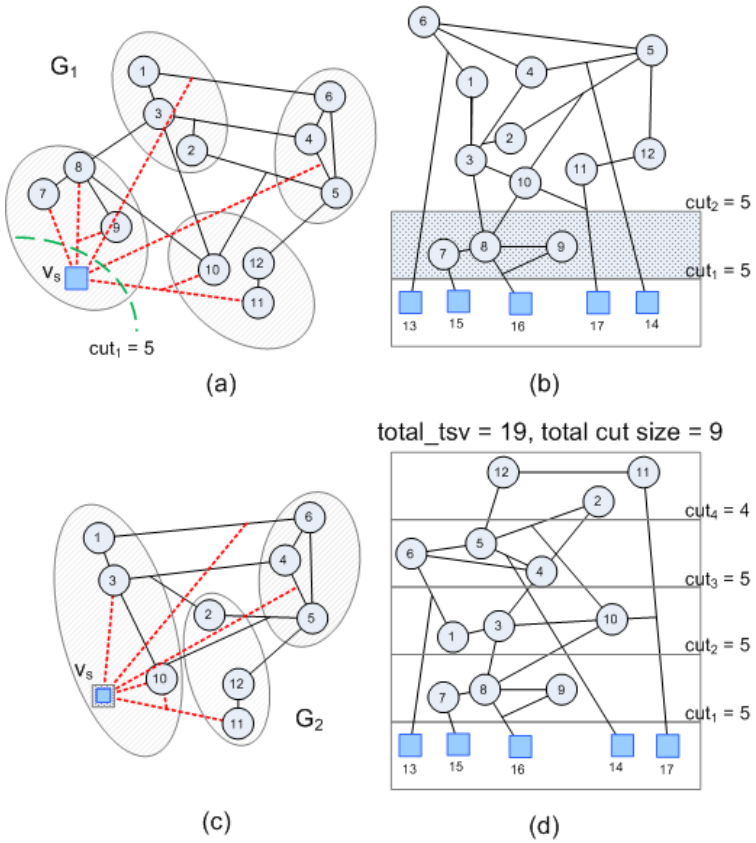


Figure 6. (a) Compact I/O pads into v_s then apply 4-way partitioning, (b) assign {7, 8 ,9} to L_1, (c) compact L_1 into v_s then apply 3-way partitioning, and (d) show the final layering result

further suggests that the cells residing in p_s should be located as close to the I/O pads as possible for cut minimization and thus should be assigned to L_1. For example, the four dashed circles in Fig. 6(a) indicate the 4-way area-balanced min-cut partitioning result, and hence L_1 is ultimately set to {7, 8, 9} as Fig. 6(b) depicts.

Similarly, once the elements of L_1 are determined, cut_2 is therefore fixed. The next task then becomes how to decide which vertices should reside in L_2. Again, since L_0 and L_1 are fixed at this point, jct_2 and cut_2 are both fixed no matter how other remaining cells (or L_2~L_k) get partitioned later. As one can easily discover that the situation here is very similar to that of identifying L_1 previously. Hence, if we further derive G_2 from G_1 by compacting L_1 into v_s and apply (k–1)-way min-cut partitioning on G_2, L_2 can then be identified in the same fashion (as shown in Fig. 6(c)). That is, at each iteration our proposed algorithm always derives G_{n+1} from G_n by further compacting L_n into v_s, then applies (k–n)-way area-balanced min-cut partitioning to get L_{n+1}. This iterative process is not terminated until L_{k-1} is identified. Fig. 6(d) illustrates the final result generated by the proposed algorithm, and the total TSV count is merely 19, which is smaller than those in Fig. 3(b) and 3(c) (28 and 21, respectively).

The proposed framework possesses following four unique features:

- It invokes multi-way min-cut partitioning at every iteration. The major reason is to find the set of cells closest to the previously identified junctions, which potentially minimizes the TSVs of the current junction. To better mimic the final solution, min-cut partitioning helps distribute TSVs more evenly among all layers and hence potentially results in a more stable outcome.

- Once a junction (and thus a cut) is fixed at some iteration, it is never altered at the following iterations. This ensures that good decisions made previously are never overthrown later.
- At each iteration, only one partition is accepted and decisions for other partitions are actually discarded. Later, the updated graph topology is reexamined and better decisions are thus dynamically reacquired at the following iterations. For instance, $L_2 = \{1, 3, 10\}$ in Fig. 6(d) is not identical to any partition shown in Fig. 6(a). As a consequence, applying any one of conventional multi-way min-cut partitioning algorithms just once cannot get this kind of result.
- From the traditional partitioning perspective, the result in Fig. 6(d) has a larger total cut size than the result given in Fig. 3(a) (9 vs. 8). However, we already show that the former one is actually a better 3D partitioning solution. Hence, it is obvious that the total cut size, which is layer-unaware, is apparently not an appropriate metric in 3D partitioning. Again, this is another evidence that classical multi-way min-cut partitioning algorithms can hardly compete with the proposed iterative framework.

In this work, we adopt the well-known hMetis as the internal partitioning engine since it is one of the best partitioning engines we can find today. However, our proposed framework can obviously co-work with any multi-way min-cut partitioning engines. It implies that a better engine (if any) may be adopted for better 3D partitioning results in the future.

The pseudo code of the complete algorithm is given in Fig. 7. All I/O pads are first compacted into a supervertex v_s during initialization. Each iteration starts with (k–n+1)-way min-cut partitioning. Once partitioning is done, the vertices residing in the partition where v_s is present are assigned to the current layer, i.e., Layer n. The number n always increases by one at every iteration end. At the final iteration, where $n = k$–1, the elements of Layer k–1 are identified after 2-way partitioning. Finally, the remaining cells are then automatically assigned to the topmost Layer k and the algorithm ends. That is, exact k–1 invocations of multi-way min-cut partitioning are required for getting one k-layer 3D partitioning result here.

```
Initialization
1  n ← 1;
2  compact all I/O pads into a supervertex v_s;
3  C ← C ∪ {v_s};
Constructive Loop
4  while(n < k)
5        (k–n+1)-way min-cut partition(C);
6        foreach v_i ∈ C – {v_s} do
7              if part(v_i) == part(v_s) do
8                    assign v_i to Layer n;
9                    C ← C – {v_i};
10                         compact v_i into v_s;
11             n ←n + 1;
12       foreach v_j ∈ C – {v_s} do
13             assign v_j to Layer k;
```

Figure 7. Pseudo code of *iLap*.

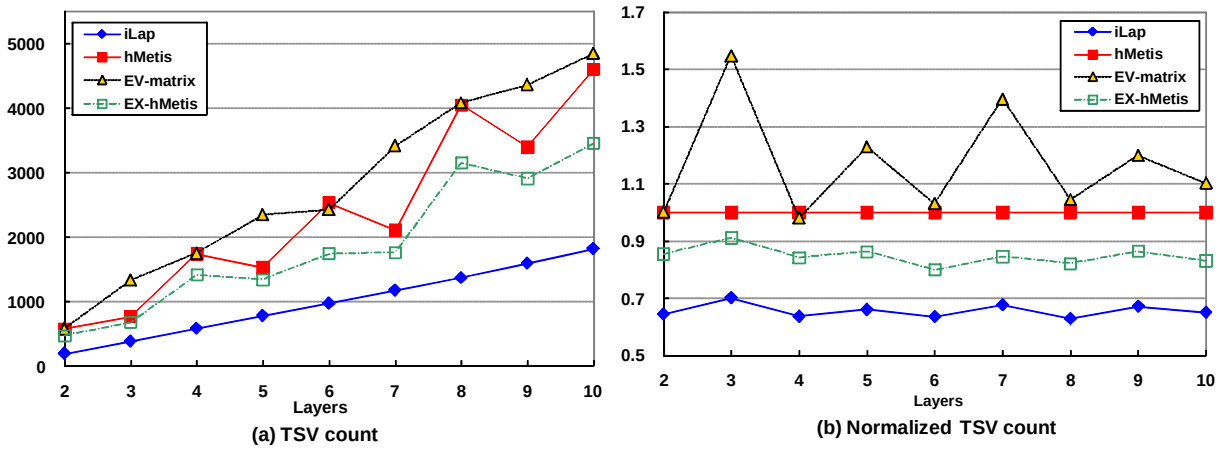


Figure 8. The number of required TSVs in different layers.

C. Experiments

1. Benchmarks and Experiment Setup

iLap has been implemented in C++/Linux environment. We demonstrate the effectiveness of *iLap* through a series of comparisons with three hMetis-based methods: 1) *hMetis*: partitions are further layered according to their original sequential tags (i.e., in random order basically); 2) *EX-hMetis*: partitions are best layered through exhaustively examining all possible layer permutations; 3) *EV-matrix*: partitions are layered by the method described in [26]. Note that the three hMetis-based methods all start with the same set of partitions and thus the variances among their final results solely come from different layer assignments. We evaluate the performance of *iLap* and other three methods over a set of 14 test cases, consisting of 10 cases from the MCNC benchmark set [30], three large cases (*cfft*, *aqua*, and *video*) from Altera [31], and one in-house 128-point FFT design (*fft128*). They are intended to mimic complicated system designs integrating a large number of functional blocks. The number of blocks ranges from 1,047 to 53,491. Since the test cases selected in our experiments are all far larger than those used in [22], comparisons between *iLap* and the ILP-based approach proposed in [22] are therefore omitted in this paper. We perform ten experiment runs on every test case with different random seeds and take the average as the final result.

2. Results and Analyses

A set of experiments are conducted with various number of layers ranging from two to ten. Table I reports the TSV demands as the number of layers is set to 4. It seems *EV-matrix* just performs equally well as plain *hMetis*. Meanwhile, given a set of 4 partitions generated by hMetis, *EX-hMetis* always picks the one with the lowest TSV count out of 4! = 24 different layer permutations and consequently *EX-hMetis* on average attains 16% TSV reduction as compared with *hMetis*. Nevertheless, *iLap* can reduce TSV count by 36% and 24% on average as compared to *hMetis* and *EX-hMetis*, respectively. Moreover, for the largest three test cases (*cfft*, *aqua*, and *video*), *iLap* even outperforms *hMetis* by more than 75%. Though *hMetis* is an excellent multi-way min-cut partitioning algorithm, unfortunately it fails to be a good 3D partitioner due to its layer-unawareness. Even *EX-hMetis*, with exhaustive layer permutations, still cannot

defeat *iLap*. Therefore, it concludes that a dedicated layer-aware 3D partitioning algorithm, like *iLap*, should be regarded as one of the essential components while constructing a sophisticated 3D IC design environment.

Next, Fig. 8(a) depicts the average TSV count over 14 test cases as a function of the number of layers; and three points are worth pointing out. Firstly, the more layers a design gets partitioned into, the more TSVs it generally requires. Secondly, *iLap* is the all-time winner from 2 layers to 10 layers among four methods. Thirdly, unlike the other three methods, the number of TSVs required by *iLap* raises very smoothly as the number of layers increases. Taking *hMetis* as the baseline, Fig. 8(b) reveals the average ratios of TSV count over the number of layers; and two points are worth mentioning here. Firstly, *iLap* constantly and steadily outperforms *hMetis* by about 35% in TSV count regardless of the number of layers. Secondly, *EX-hMetis* always outperforms *hMetis*, as expected.

Meanwhile, Fig. 9(a) presents the average standard deviations of TSV count over a different number of layers. Through constructing its outcome layer by layer, *iLap* can better balance the TSV count among junctions. From Fig. 9(a), it is evident that the standard deviation of TSV count associated with *iLap* is far better than those of the other three. As previously mentioned, a TSV occupies significant silicon estate so that high standard deviation of TSV count potentially worsens area imbalance among individual layers and even lowers the yield of a design. Fig. 9(b) reports the average maximum TSV count at some junction of a design over a different number of layers; and *iLap* always possesses the lowest values regardless of the number of layers. In other words, a lower TSV count implies a smaller total area (including TSV area) after partitioning, and a smaller standard deviation of TSV count results in a more area-balanced partitioning outcome. The above two facts suggest that *iLap* tends to generate a smaller overall footprint of a 3D chip implementation. From another perspective, for some 3D logic

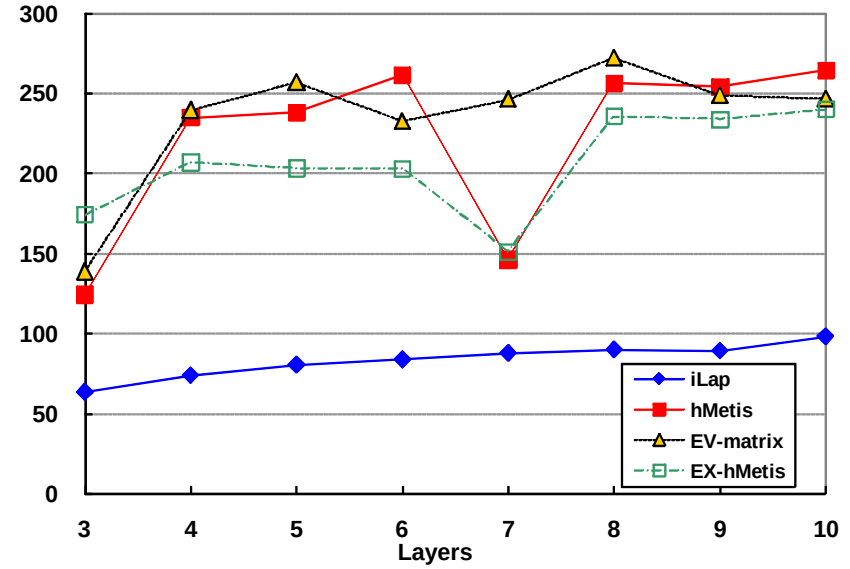
TABLE I. TOTAL NUMBER OF TSVS WITH K = 4

4 layers	***Total TSVs**				**Normalized to hMetis**		
Design	iLap	hMetis	EV-matrix	EX-hMetis	iLap	EV-matrix	EX-hMetis
Tseng	304.2	356.3	361.2	346.1	0.85	1.01	0.97
Diffeq	244.9	344.5	351.0	270.3	0.71	1.02	0.78
Des	445.5	857.5	876.1	834.5	0.52	1.02	0.97
Bigkey	629.2	666.2	669.2	650.6	0.94	1.00	0.98
Frisc	655.2	714.1	719.0	688.7	0.92	1.01	0.96
elliptic	590.3	709.9	690.0	643.1	0.83	0.97	0.91
pdc	973.4	1049.5	1059.0	986.8	0.93	1.01	0.94
fft128	1313.9	1506.0	1524.8	1489.2	0.87	1.01	0.99
s38417	249.4	364.7	389.6	324.6	0.68	1.07	0.89
s38584.1	391.4	673.8	762.6	536.7	0.58	1.13	0.80
clma	491.4	721.2	654.6	496.5	0.68	0.91	0.69
cfft	244.4	999.2	480.3	338.5	0.24	0.48	0.34
aqua	909.6	7026.5	7167.4	4935.8	0.13	1.02	0.70
video	763.8	8370.7	8757.1	7255.0	0.09	1.05	0.87
Average	-	-	-	-	0.64	0.98	0.84

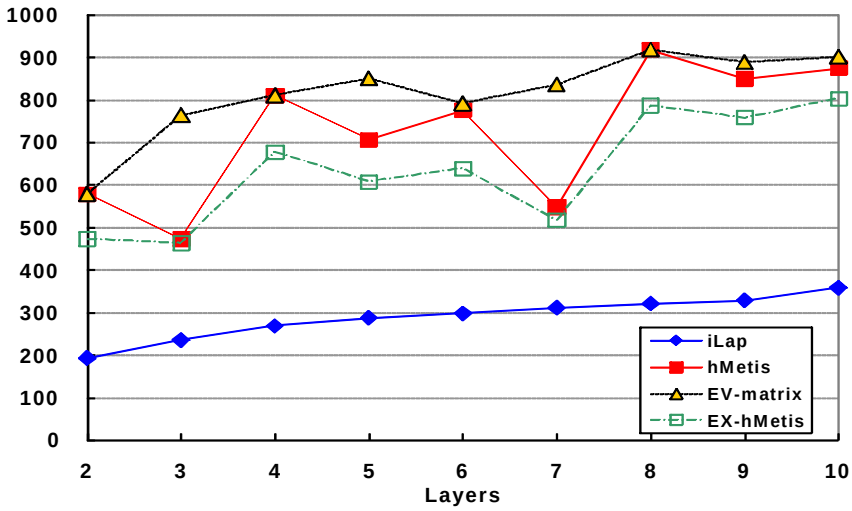
*The reported number is the average of 10 experiment runs.

structures, like 3D FPGAs, the number of pre-fabricated inter-layer TSVs is fixed. Hence a design mapping attempt is considered a failure as long as the required TSVs exceed the available ones only at one junction; and a high maximum TSV count definitely increases such chances. Lower maximum TSV count is considered a big plus especially in design flows for 3D regular logic structures such as 3D FPGAs.

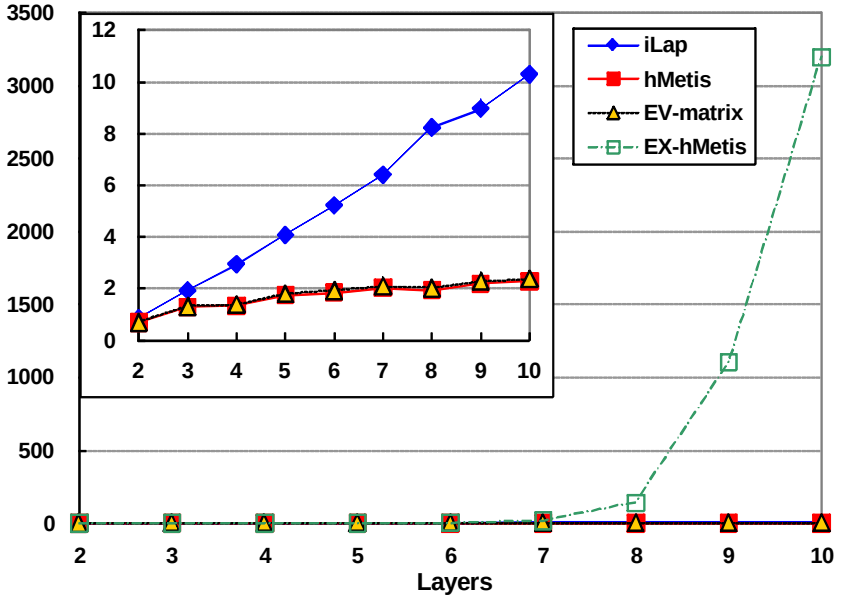
Regarding the runtime efficiency issue, Fig. 9(c) gives the average runtime of 14 test cases in second over a different number of layers. It is evident that both *hMetis* and *EV-matrix* are very time-efficient. The runtime required by *iLap* grows linearly as the number of layers increases. It is mainly because the number of invocations for multi-way partitioning inside *iLap* also grows linearly as the number of layers increases. However, given the tremendous performance in TSV minimization, the time complexity of *iLap* should be acceptable. For example, it only takes about fifty seconds for *iLap* to partition the largest test case *video* into ten layers. As for *EX-hMetis*, since it has to check all possible layer permutations to find out the best one, the required runtime is thus exponential to the number of layers. Even if *EX-hMetis* can be further improved (e.g., by pruning) so that not all permutations need to be examined, the improvement is limited to runtime efficiency only, while other TSV-related performance would still remain the same.



(a) Standard deviation of TSV count



(b) Maximum TSV count



(c) Runtime (seconds)

Figure 9. More statistics from the experiments.

A. Architectures and synthesis framework for 3D FPGAs

A classic 2D FPGA is composed of logic elements (configurable logic blocks, CLBs) and routing resources (switch boxes, SBs; connection boxes, CBs). The basic unit is called a *tile*, which consists of a CLB, an SB, and associated CBs. As shown in Fig.10, the generic 3D FGPA architecture in this work is similar to the one used in TPR and 3D MEANDER, which basically stacks multiple identical 2D FPGA layers and then extends the structure of 2D-SB to provide inter-layer connectivity. *Fs* is set to 3 in a 2D-SB and 5 in a 3D-SB, where *Fs* is the maximum allowable fan-outs of a channel in an SB.

The reference synthesis flow used in this work is shown in Fig. 11. A given design (in blif format) is first packed into a netlist file composed of CLBs by T-VPack, which is a part of the 2D FPGA synthesis framework VPR [32][33]. The netlist file is then fed into a 3D FPGA synthesizer, which includes three steps: initial layering, timing-driven 3D placement and 3D routing. The initial layering partitions the netlist into different layers with the objective of TSV minimization [34]. The 3D placement and routing processes, which are adapted from TPR, are then conducted on the layered netlist. The framework also takes an input file, setting the architectural parameters of the target 3D FPGA, and generates the placement and routing results in the end.

B. Evaluation environment

1. Architectural Settings

The basic architectural settings are shown in TABLE II. Most of the parameters are set according to existing commercial FPGAs, well-known FPGA synthesizers, and related

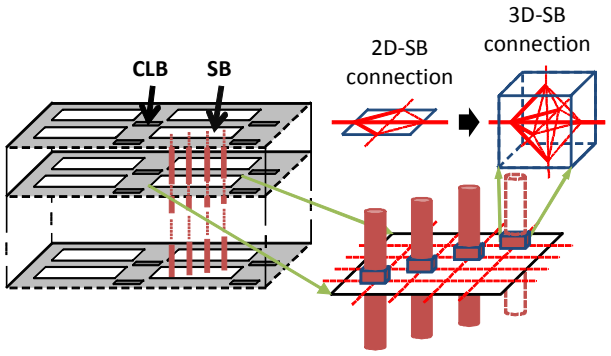


Figure 10. The gereric 3D FPGA architecture.

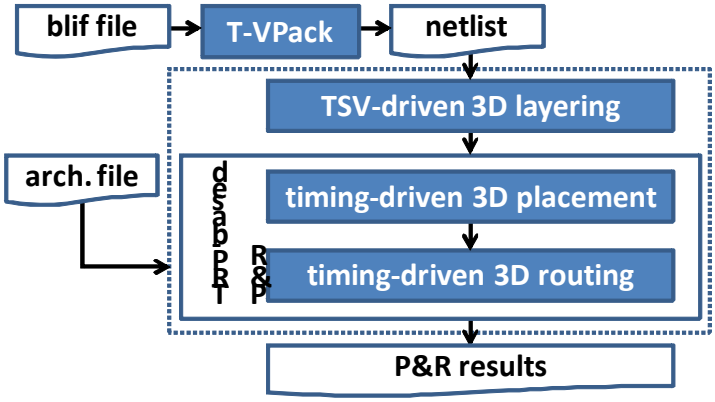


Figure 11. The reference synthesis framework.

TABLE II. THE ARCHITECTURAL SETTINGS

Architectural Parameters			Value
CLB *(Altera Stratix IV)*	# of LUTs in a CLB (*N*)		2
	# of inputs of a CLB (*I*)		8
	# of inputs of a LUT (*K*)		6
SB *(Xilinx Spartan)*	Connection type		Subset
Channel width *(Xilinx)*	Both W_X and W_Y		32
# of wire segments	X-Y direction	(*L1*, *L2*, *L4*, *L8*)	(12, 12, 4, 4)
	Z direction	*L1* only	-
Delay model	$L1_Z : L1_{X\text{-}Y}$		1 : 10
TSV	Pitch		10 um
Process Technology			65 nm

TABLE III. THE BENCHMARK INFORMATION (PARTIAL)

Design	# CLBs	# Nets	# I/Os
s38584.1[1]	3224	5419	342
clma[1]	4192	6869	144
mem_ctrl_0mv_b[2]	7344	10865	265
usb_funct_0mv_b[2]	7440	11372	234
tv80_0abc_ch[2]	8809	12987	46
b20[3]	9844	15557	55
b21[3]	10016	15713	55
aes_core[2]	10400	16706	386
oc_des_perf_opt_opt_abc_resyn[4]	10641	17150	185
systemcaes_0abc_ch[2]	13480	19634	388
b22[3]	14585	23114	55
b17[3]	15390	24986	135

[1]: MCNC; [2]:IWLS2005; [3]: ITC99; [4]: Altera

research works [26][27][29], [35]–[38]. The number of LUTs (lookup tables) in an CLB (*N*) is set to 2 instead of 1 in the previous works [26][29], which is considered more realistic. The channel widths in the X-Y directions are both set to 32; the multi-segment routing structure is adopted: the possible wire lengths are *L1*, *L2*, *L4* and *L8*; and the numbers of channels are 12, 12, 4 and 4, respectively. In the vertical direction (Z), only *L1* is available to maximize the routability. Finally, I/O pads are located only around the bottom-most layer.

2. Benchmark Set

There are 24 test cases in our benchmark set – 14 are from MCNC and the other 10 larger ones are from IWLS2005, ITC99 and Altera [30][31]. The basic information for a

partial set of test cases is shown in TABLE III; the numbers of CLBs and nets are derived from T-VPack with the parameters (N, I, K) = (2, 8, 6), which is specified in TABLE II.

In our evaluation environment, the X-Y dimension (D) of a 3D FPGA architecture varies according to the number of layers (L) and the overall capacity of CLBs (C), as given in (1):

$$D = \left\lceil \sqrt{C/L} \right\rceil \qquad (1)$$

During every evaluation run, the capacity of CLBs (C) is dynamically adjusted to ensure that the value is around 80%.

3. Baseline Architecture (BSL)
   In the baseline architecture, every SB is a 3D-SB; and every 3D-SB is with *full vertical connectivity*, which means there are 32 TSVs (identical to the number of channels in the X-Y direction) within a 3D-SB. In the BSL, though the vertical routability is maximized (which is best to delay), the utilization of TSVs is extremely low (< 10%) as indicated in Fig. 5. This fact also suggests there is still a big room for further architecture improvements. Hereafter in this paper, the BSL would serve as a baseline for comparisons with the proposed architectures in the next two sections.

C. Proposed sparse architectures

Basically there are two ways to reduce the area occupied by 3D-SBs in a 3D FPGA. The first one is to decrease the number of TSVs in a 3D-SB. Such kind of 3D-SBs are called *partially*

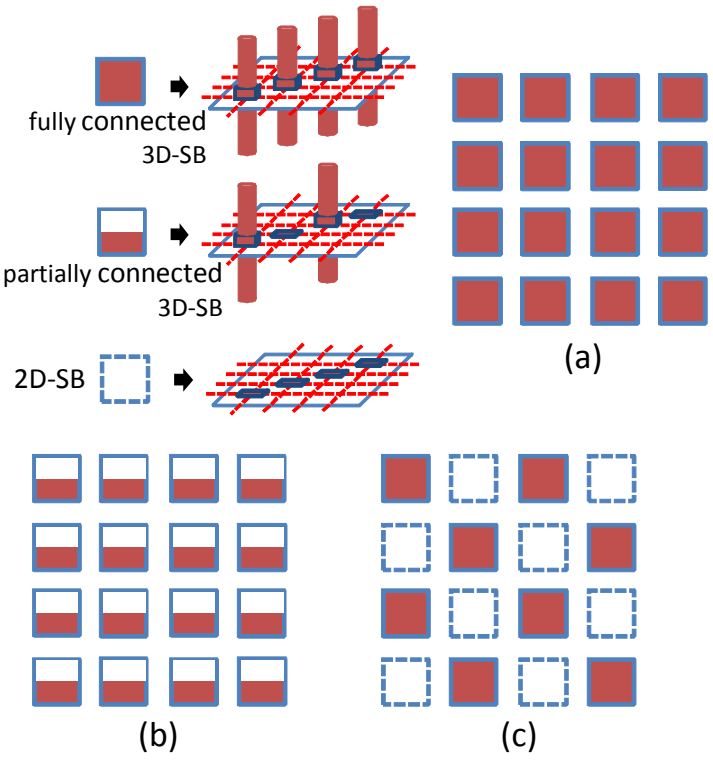


Figure 12. The different SB patterns of (a) BSL, (b) IS, and (c) ES.

connected 3D-SBs. The other one, also used in 3D MEANDER, is to reduce the number of 3D-SBs in a 3D FPGA. That is, some SBs become 3D ones, and others are still 2D ones. The *internally-spare* (*IS*) architectures are those utilizing the former method, while the *externally-sparse* (*ES*) ones are those utilizing the latter method. Different configurations of SBs, also referred as *patterns* in this paper, are shown in Fig. 12. In the BSL, as shown in Fig. 12(a), all SBs are fully connected 3D-SBs. An IS architecture adopts the same type of partially connected 3D-SBs for all SBs instead, as in Fig. 12(b). In an ES architecture as shown in Fig. 12(c), fully connected 3D-SBs are partially distributed in a regular fashion. Note that the patterns are set identical for all layers in all proposed architectures. In addition to IS and ES architectures, the *sparse architecture* (*SP*), which is a hybrid of the above two, is proposed to further reduce the area. More details and evaluations are available in the following sub-sections.

1. Internally-Sparse Architecture (IS)

   IS# represents an instance of the IS architecture, where the postfix # specifies the number of TSVs available in a 3D-SB. For example, every 3D-SB in *IS16* has only 16 TSVs inside, while *IS32* is actually equivalent to the BSL. As mentioned in Section III, the multi-segment routing structure is adopted and there are four different wire lengths with different amount of channels in the X-Y direction. In the BSL, it makes no differences since each X-Y channel has its own vertical connection. However, in an IS

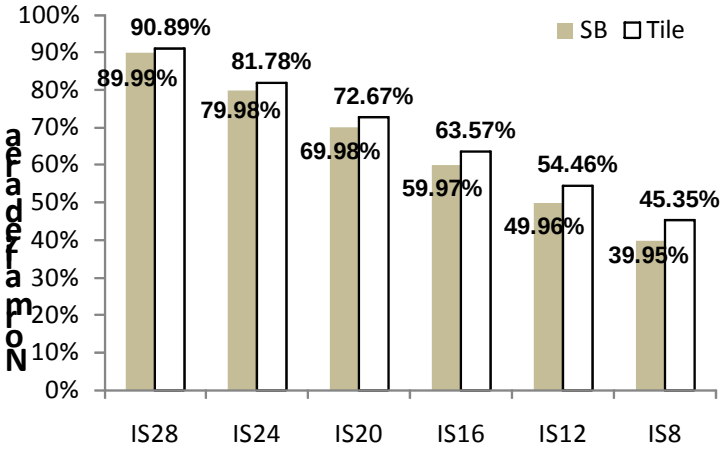


Figure 13. The normalized area of different IS architectures.

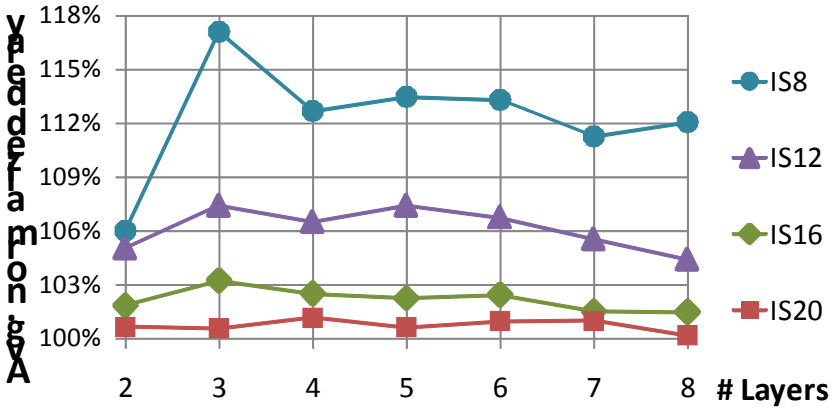


Figure 14. The average normalized dealy of different IS architectures.

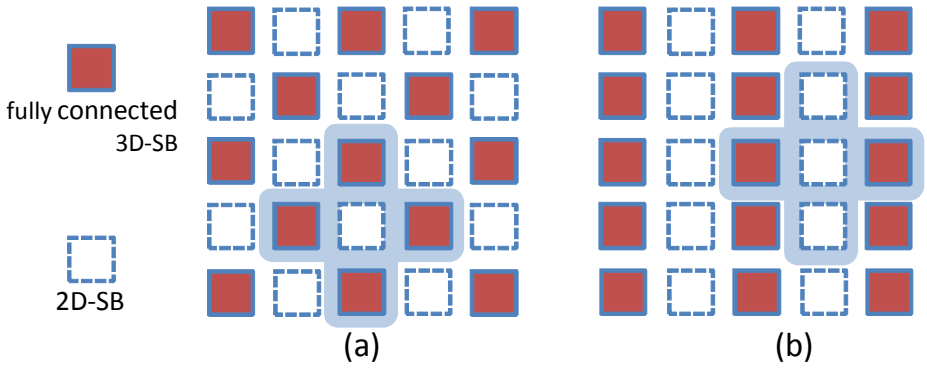


Figure 15. The ES architecture with
(a) the oblique stripes pattern and (b) the vertical stripes pattern.

architecture, some of TSVs in a 3D-SB are removed. Be precisely, the vertical connections (TSVs) are taken out from each type of X-Y channels proportionally whenever possible. For example, the numbers of channels with vertical (Z) connectivity for (*L1*, *L2*, *L4*, *L8*) are (9, 9, 3, 3) in *IS24*, while the remaining 8 channels merely provide 2D (X-Y) connectivity.

Fig. 13 reports the area of different IS architectures, in which all values are normalized to that of the BSL. It shows that both the sizes of an SB and a tile basically decrease linearly as the number of TSVs in a 3D-SB decreases. However, though reducing the number of TSVs in an 3D-SB can save area, it is very likely to harm delay at the same time. To realize what the exact impact on delay is, the benchmark circuits are mapped onto different IS architectures and the BSL through the reference synthesis framework. Fig. 14 illustrates the delay of different IS architectures, in which every value represents the average of normalized-to-the-BSL delay over the entire benchmark set. Since the curves of *IS28*, *IS24*, and *IS20* are almost overlapped therefore only the one of *IS20* is depicted. Note that some test cases fail to be mapped onto *IS12* due to insufficient vertical routing channels. Most of the test cases fail in *IS8*; one even succeeds, the delay increases significantly. Finally, since *IS20* achieves about 30% overall area reduction only with a delay penalty less than 1.5% as compared to the BSL, it should be the one with a better area/delay balance among all IS architectures.

2. Externally-Sparse Architecture (ES)

   An ES architecture replaces a part of fully connected 3D-SBs with 2D-SBs for area saving. There are various ways, or *patterns*, for mixing 2D-SBs and 3D-SBs. The pattern used in the ES architecture is *oblique stripes*, which is the same as the one used in 3D MEANDER. *ES#* represents an instance of the ES architecture, where the postfix # specifies the maximum *distance* between two adjacent 3D-SBs in either X or Y direction. Therefore, *ES1* is actually equivalent to the BSL, and *ES2* is the one shown in Fig. 15(a).

   Different from the vertical or horizontal stripes patterns, it is guaranteed that each 3D-SB in the oblique stripes pattern can reach some other 3D-SBs within a fixed distance in any directions, which surely provides much better routability. From the perspective of a 2D-SB, the shaded region covers the area where a 2D-SB can access vertical links in the

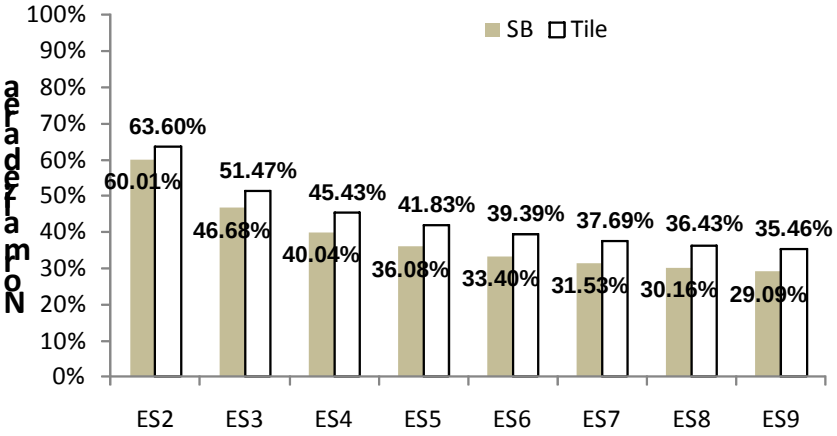


Figure 16. The normalized area of different ES architectures.

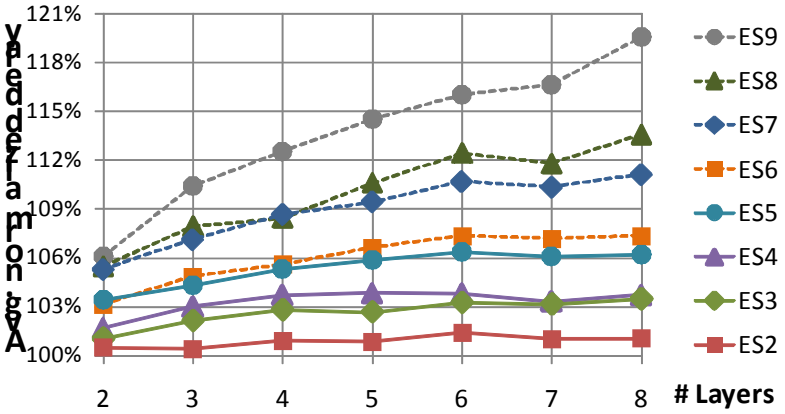


Figure 17. The average normalized dealy of different ES architectures.

shortest distance as shown in Fig. 15(a). However, with the same shaded region, only two 3D-SBs can be reached for a 2D-SB in an architecture with vertical stripes patterns, as shown in Fig. 15(b). The analyses and conclusions are also similar also from the perspective of a 3D-SB.

Fig. 16 reports the area of different ES architectures. As the distance increases, the area reduction is significant at first and then becomes flat gradually. The curve appears like a harmonic sequence. Fig. 17 illustrates the delay of different ES architectures. As the distance increases, the delay is increased badly. As a result, *ES2*, *ES3* and *ES4* are all regarded as good instances since they can achieve around 35%~55% area reduction only with a delay penalty less than 5%. Moreover, if the delay penalty is constrained below 3%, *ES2* becomes the best choice because it achieves an area reduction of 35% with a delay penalty less than 1.5%.

3. Sparse Architecture (SP)

For IS and ES architectures, we try to reduce the area with just a single strategy – either purely reducing the number of TSVs in each 3D-SB or purely reducing the number of 3D-SBs. Here we present the *sparse architecture*, which takes above two strategies simultaneously. $SP(\#_1, \#_2)$ is used to name an specific instance of this hybrid architecture, which is the combination of $IS\#_1$ and $ES\#_2$. This notation can be generalized to represent IS and ES architectures as well. For example, *SP*(32, 1) is equivalent to the BSL, *SP*(16, 1) implies *IS16*, and *SP*(32, 2) is actually *ES2*. Meanwhile, the *TSV density* of an

architecture is defined as the average number of TSVs in a tile, and can be calculated through (2).

$$\text{TSV density} = IS\# / ES\# \qquad (2)$$

As mentioned, *ES4=SP*(32, 4) with TSV density of 8 is still regarded as a good instance. Note that, the lower the TSV density is, the worse the delay is likely to be. Hence, only those SP architectures with TSV density no less than 8 are selected for evaluation. Fig. 18 shows the area of selected SP architectures. As expected, the lower the TSV density is, the smaller the area is. Fig. 19 reports the delay of same selected SP architectures, and conforms that the lower the TSV density is, the worse the delay is. Finally, SP(28, 2), SP(24, 2), and SP(20, 2), are our recommended SP architectures under the constraint that the delay penalty cannot exceed 3%.

D. Proposed sunny egg architecture

Though SP(20, 2) has already achieved an area reduction of 50% with minor delay loss, there is still room for improvement. Fig. 20 shows the average TSV distribution in a 6-layer BSL over 6 test cases. The results suggest that the TSV demand is much bigger in the central region than

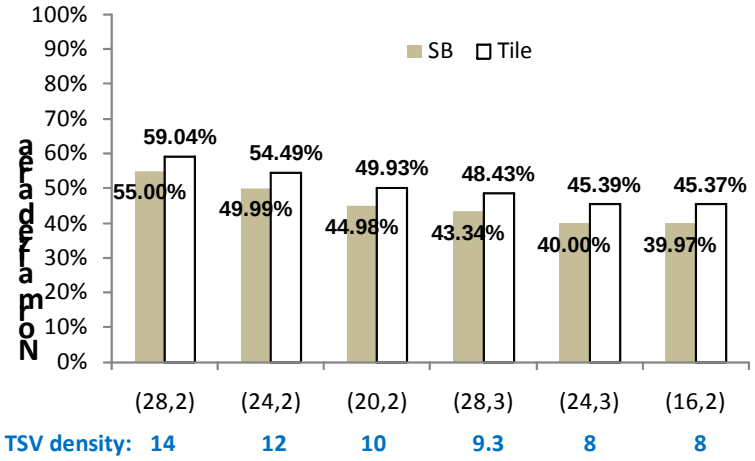


Figure 18. The normalized area of different SP architectures.

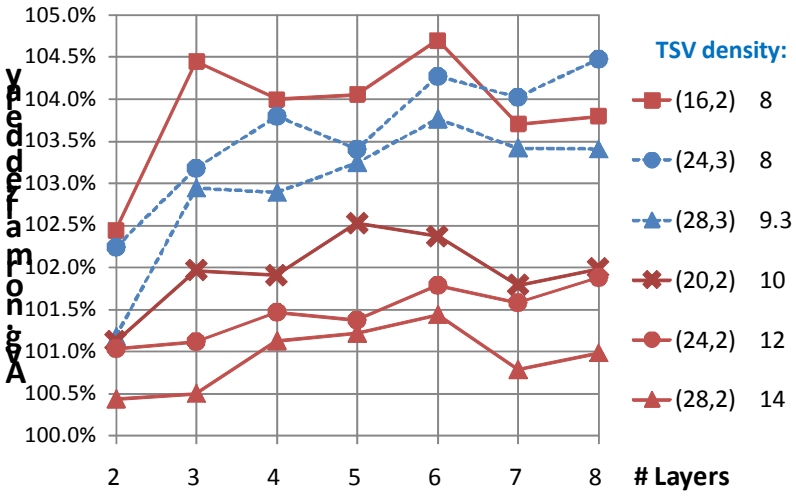


Figure 19. The average normalized dealy of different SP architectures.

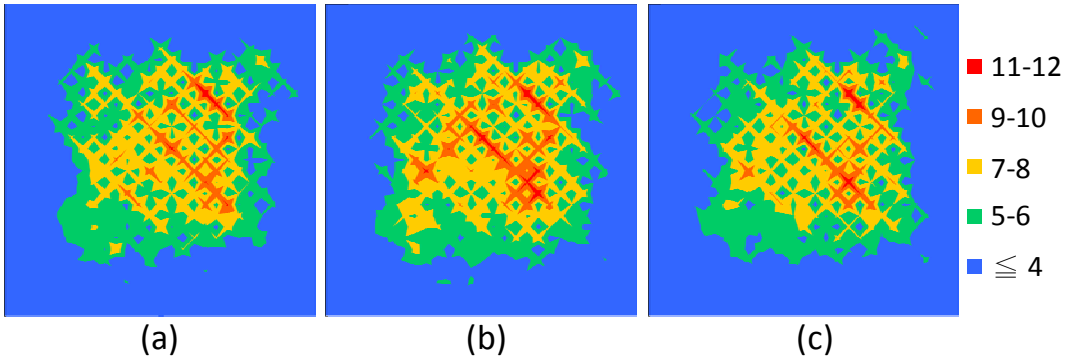


Figure 20. The average TSV utilization in a 6-layer BSL. Between: (a) Layer 2 and 3, (b) Layer 3 and 4, and (c) Layer 4 and 5.

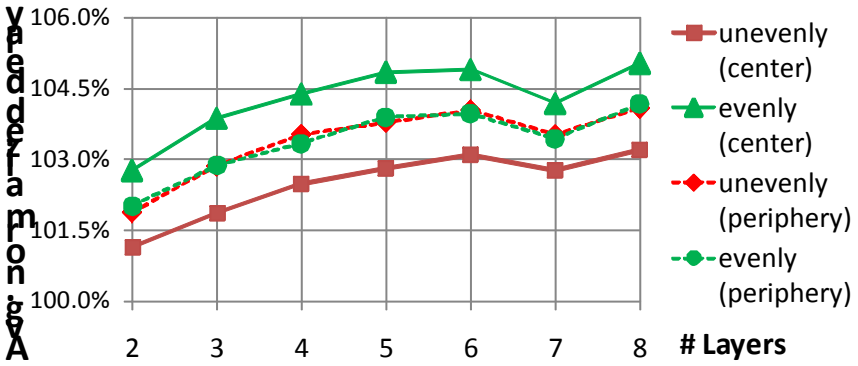


Figure 21. The average normalized dealy with different TSV distributions.

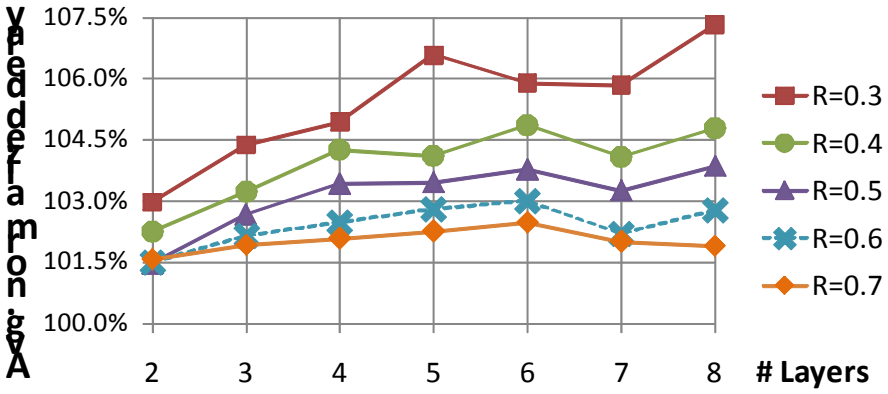


Figure 22. The average normalized dealy with different R's.

that in the peripheral zone; and thus inspire us to further propose the *sunny egg* (*SE*) architecture.

The sunny egg architecture divides a horizontal plane into two regions – center (egg yolk) and periphery (egg white). Two regions are implemented using different SP architectures – the TSV density in the center is set larger than that in the periphery. *SE*(IS_C#, ES_C#, *R*, IS_P#, ES_P#) indicates a specific SE architecture, where *SP*(IS_C# and ES_C#)/*SP*(IS_P# and ES_P#) is for the center/periphery respectively, and *R* is the ratio between the dimension of the center and *D* (defined in Section III.B). For example, *SE*(32, 2, 0.5, 16, 4) specifies an SE architecture: 1) in the central/peripheral region, the number of TSVs in a 3D-SB is 32/16 and the distance between two 3D-SBs in the X/Y directions is 2/4; and 2) the ratio between the dimension of center and *D*

TABLE IV . SE ARCHITECURES UNDER EVALUATION (PARTIAL)

IS_C#	ES_C#	R	IS_P#	ES_P#
32	2	0.3	16	4
32	2	0.3	8	2
16	1	0.3	16	4
16	1	0.3	8	2
32	2	0.7	16	4
32	2	0.7	8	2
16	1	0.7	16	4
16	1	0.7	8	2

is 0.5.

A total of 20 different SE architectures are evaluated in this study. They are generated in the following way: 2 SP instances with higher TSV densities (*SP*(32, 2), *SP*(16, 1)) for the center, 2 SP instances with lower TSV densities (*SP*(16, 4), *SP*(8, 2)) for the periphery, and *R* ranges from 0.3 to 0.7. TABLE III just lists 8 of them due to page limitation. Meanwhile, given the same TSV density, *SP*(16, 1) distributes TSVs more *evenly* than *SP*(32, 2) in the center. Similarly, *SP*(8, 2) distributes TSVs more evenly than *SP*(16, 4) in the periphery.

Fig. 21 demonstrates how the different TSV distributions can impact the delay. First, it suggests that it is better to distribute TSVs *unevenly* in the center, i.e., *SP*(32, 2) is preferred. Second, the delay is slightly better if TSVs are evenly distributed in the periphery, i.e., *SP*(8, 2) is preferred.

The ratio *R* also does matter. As mentioned previously, the TSV density in the center is always larger than that in the periphery. Hence, the bigger the ratio *R* is, the larger the footprint is. Meanwhile, as shown in Fig. 22, the delay gets better as *R* increases due to richer routing resources. Consequently, as usual, it is still a trade-off between delay and area. Again, to keep the delay penalty less than 3% compared to the BSL, *R* must be set to higher than 0.6. As a result, the best choice here should be *SE*(32, 2, 0.6, 8, 2).

All the architectures mentioned above are compared and evaluated thoroughly. The one with the smallest 3D-SBs area while keeping the performance (i.e., the delay penalty is less than 3%

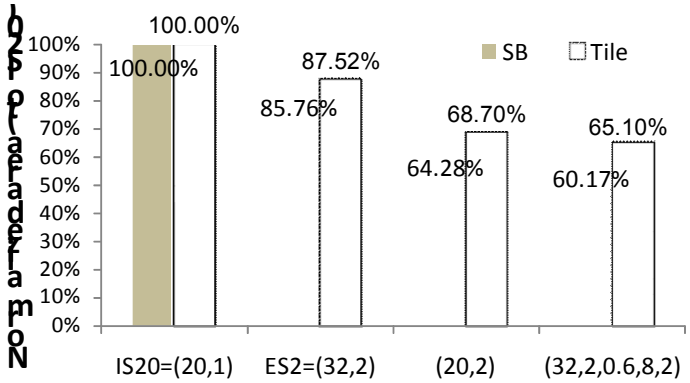


Figure 23. The average normalized area of different architectures.

compared to BSL) are chosen as the representation of each architectural style. As shown in Fig. 23, the normalized (to *IS20* instead of BSL in the previous evaluations) area consumptions of *IS20*, *ES2*, *SP*(20, 2) and *SE*(32, 2, 0.6, 8, 2) are depicted. The average normalized delay (to BSL) is shown in Fig. 24. The hybrid architectures, which utilize both the techniques of IS and ES, can save more than 35% area of SBs compared to *IS20*. Especially, the difference of delay penalty between *SE*(32, 2, 0.6, 8, 2) and *IS20* is less than 2%. Therefore, the hybrid architectures *SP*(20, 2) and *SE*(32, 2, 0.6, 8, 2) are the most recommended.

四、 結論

In this project, we present an iterative layer-aware partitioning algorithm *iLap* targeting TSV minimization for 3D structures. It utilizes a multi-way min-cut partitioning engine inside its iterative framework to gradually construct the final solution layer by layer in the bottom-up fashion. The experimental results clearly demonstrate that *iLap* is capable of reducing total TSV count by about 35% compared to layer-unaware *hMetis*, experiencing a smoother TSV increase as the number of layers raises, distributing TSVs more evenly among different vertical layers, preventing any layer junction from having a burst number of TSVs, and only requires an acceptable runtime. Consequently, compared to the prior art, we believe *iLap* can generate a better TSV-minimized solution, which serves as a good starting point for further tradeoff between wirelength and number of TSVs in upcoming state-of-the-art 3D IC/FPGA design flows.

Moreover, we show that the utilization of TSVs is actually very low in the baseline 3D FPGA architecture where the fully connected 3D-SBs are fully distributed. Therefore the area of 3D FPGAs can be further reduced while the performance is still guaranteed. There are two simple approaches to reduce the area of 3D-SBs. The internal-sparse architecture (IS) is to reduce the number of TSVs in each single 3D-SB and the external-sparse 3D-SBs architecture (ES) is to reduce the number of 3D-SBs. The hybrid methods, including sparse architecture (SP) and sunny egg (SE), are also proposed to further minimize the area of 3D FPGAs by using the techniques of IS and ES at the same time. Those architectures are explored thoroughly and evaluated objectively. After comparing all these architectures, two generic 3D FPGA architectures are suggested, that is, the SP architecture (20, 2) and SE architecture (32, 2, 0.6, 8, 2), which save the most area with acceptable delay penalty. *SP*(20, 2) reduces 55% (to BSL) and 35% (to *IS20*) of SB area; *SE*(32, 2, 0.6, 8, 2) reduces 58% (to BSL) and 39% (to *IS20*) of SB area. Both of them are with (less than) 3% increase delay.

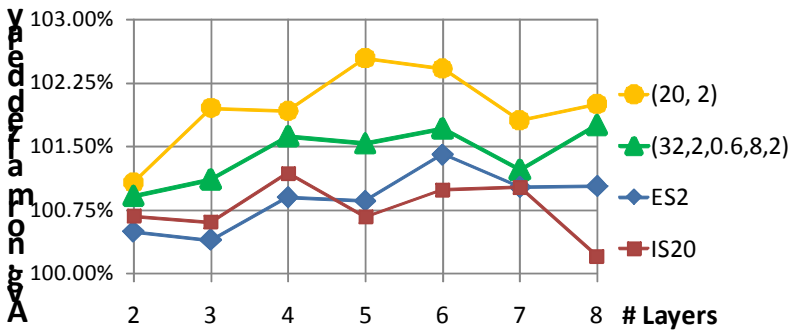


Figure 24. The average normalized dealy of different architectures.

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六、 成果自評

我們於計劃第二年的這段期間（99 年 8 月 1 日至 100 年 7 月 31 日），在學術論文發表方面，在今年度我們發表了以下**國際會議論文**：

1. Ya-Shih Huang and **Juinn-Dar Huang**, “Throughput-Driven Hierarchical Placement for Two-Dimensional Regular Multicycle Communication Architecture,” Asia Symposium on Quality Electronic Design, pp. 134 – 139, Aug. 2010.
2. Ya-Shih Huang, Yang-Hsiang Liu, and **Juinn-Dar Huang**, “Iterative 3D Partitioning for Through-Silicon Via Minimization,” Proc. of the 16th Workshop on Synthesis and System Integration of Mixed Information Technologies, pp. 154 – 159, Oct. 2010.

3. Chia-I Chen, Bau-Cheng Lee, **Juinn-Dar Huang**, "Architectural Exploration of 3D FPGAs towards a Better Balance between Area and Delay," Proc. of Design, Automation & Test in Europe Conference and Exhibition, pp. 587 – 590, Mar. 2011. (Best Paper Candidate)
4. **Juinn-Dar Huang**, Yi-Hang Chen, and Wan-Hsien Lin, "Performance-Optimal Behavioral Synthesis with Degenerable Compound Functional Units," Proc. of IEEE International Symposium on VLSI Design, Automation, and Test, pp. 337–340, Apr. 2011.
5. Ya-Shih Huang, Yang-Hsiang Liu and **Juinn-Dar Huang**, "Layer-Aware Design Partitioning for Vertical Interconnect Minimization," Proc. of IEEE Computer Society Annual Symposium on VLSI, pp. 144 – 149, Jul. 2011. (Best Paper Award)

還有以下國內會議論文：

1. Ya-Shih Huang, Yang-Hsiang Liu, and Juinn-Dar Huang, "Layer-Aware Partitioning for Through-Silicon Via Minimization in 3D ICs," Proc. of the 21st VLSI Design/CAD Symposium, Aug. 2010.

在專利方面，通過以下國內外專利：

1. **黃俊達**，林步青，李耿維，周景揚，"精細頻寬調控的仲裁器及其仲裁方法" 中華民國專利案號 I332615，2010 年 11 月 1 日。
2. **Juinn-Dar Huang** and Chia-I Chen, "Dynamical sequentially-controlled low-power multiplexer device," US 7881241 B2, Feb. 2011.
3. **黃俊達**，陳嘉怡，"低功率動態序向控制多工器" 中華民國專利案號 I342670，2011 年 5 月 21 日。

並有以下專利正在申請中：

1. **黃俊達**、呂智宏、林步青、周景揚，"應用於查找表式 FPGA 的壓縮樹延遲最佳化"。
2. **黃俊達**、王毓翔、林步青、周景揚，"可參數化管線式快速傳利葉轉換硬體產生器"。
3. **黃俊達**、呂智宏、林步青、周景揚，Delay optimal compressor tree synthesis for LUT-based FPGAs

.

和我們當初在計劃提案中的預計的目標相比較，我們自評今年度計劃的完成度相當不錯,其中更有一篇論文獲得 ISVLSI 2011 會議之最佳論文獎(Best paper award)，一篇論文於 VLSI-DAT 2011 會議中獲最佳論文候選(Best paper candidate)，在學術論文發表及專利方面皆有不錯的表現，。

可供推廣之研發成果資料表

□ 可申請專利　■ 可技術移轉　　日期：100 年 10 月 31 日

國科會補助計畫	計畫名稱： 針對三維規則型邏輯結構之架構探索及穩健合成系統開發 計畫主持人：黃俊達 副教授　國立交通大學電子系 計畫編號：NSC99－2220－E－009－037－ 學門領域：微電學門
技術/創作名稱	適用於三維電路之層級感知矽穿孔最小化設計分割法 (Layer-Aware Design Partitioning for Vertical Interconnect Minimization)
發明人/創作人	黃雅詩、劉揚翔、黃俊達
技術說明	中文： 我們針對三維積體電路發展一套能夠最佳化矽穿孔數目之迭代式層級感知分割演算法。此演算法應用多路最小切割法將電路以迭代的方式逐層分配至適合的層級中，使其更能考慮全域的分佈狀況，而達到更好的效果。同時也在不違反輸入及輸出腳位必須在晶片底層的限制下，進而改善三維的積體電路。
	英文： We propose an iterative layer-aware partitioning algorithm, named *iLap*, for TSV minimization in 3D structures. *iLap* iteratively applies multi-way min-cut partitioning to gradually divide a given design layer by layer in the bottom-up fashion. Meanwhile, *iLap* also properly fulfills a specific I/O pad constraint incurred by 3D structures to further improve its outcome.
可利用之產業 及 可開發之產品	1. Electronic Design Automation (EDA) (EDA 產業) 2. Integrated Circuit Design (IC 設計產業)
技術特點	針對三維積體電路的結構及腳位限制，並考量面積龐大的矽穿孔所造成的影響，有效且快速的在分配電路時減少矽穿孔所需數目，並且能夠迅速的代換核心分割法，延伸至各種不同分割目標而產生設計者所需的結果。
推廣及運用的價值	此演算法能夠幫助設計三維電路時能具有較低的使用面積。這項優點不管是針對特定用途而設計的特殊應用積體電路(ASIC)或是規則型架構的電路來說，都可以減少面積以及資源上的損失並且提高生產良率及可靠度。

※ 1.每項研發成果請填寫一式二份，一份隨成果報告送繳本會，一份送　貴單位研發成果推廣單位（如技術移轉中心）。

※ **2.本項研發成果若尚未申請專利，請勿揭露可申請專利之主要內容。**

※ 3.本表若不敷使用，請自行影印使用。

可供推廣之研發成果資料表

□ 可申請專利　■ 可技術移轉　　日期：100 年 10 月 31 日

國科會補助計畫	計畫名稱： 針對三維規則型邏輯結構之架構探索及穩健合成系統開發 計畫主持人：黃俊達 副教授　國立交通大學電子系 計畫編號：NSC99－2220－E－009－037－ 學門領域：微電學門
技術/創作名稱	為取得面積與延遲間較佳平衡之三維可程式邏輯閘陣列架構探索 (Architectural Exploration of 3D FPGAs towards a Better Balance between Area and Delay)
發明人/創作人	陳嘉怡、李寶鑑、黃俊達
技術說明	中文： 將標準的二維可程式邏輯閘陣列(2D FPGAs)使用同樣的方式，將訊號切換模式從二維的架構拓展至三維，而構成三維可程式邏輯閘陣列(3D FPGAs)架構。並藉由適當調整三維切換箱的排列方式以及其內部直通矽穿孔的連接數目，可以犧牲極少量時間延遲而大幅度的減少所佔面積。
	英文： We propose a generic 2D FPGA architecture can evolve into a 3D one by extending its signal switching scheme from 2D to 3D. Furthermore, by conducting architectural explorations for 3D FPGAs, we greatly reduce the footprint with only minor delay increase by properly tailoring the structure and deployment strategy of 3D-SBs.
可利用之產業及可開發之產品	1. Electronic Design Automation (EDA) (EDA 產業) 2. Integrated Circuit Design (IC 設計產業)
技術特點	針對三維可程式邏輯閘陣列提供了一個完整的架構探索。探討在不同的切換箱架構下因矽穿孔的分布不同而造成時間延遲的交互影響，並且利用典型分布的結論提出節省硬體資源之複合型的架構。
推廣及運用的價值	提出省面積的新架構，並針對同一架構內不同的直通矽穿孔擺放方式做一個完整評估，目的是為了找出在不同架構內面積與時間延遲間更具平衡的擺放方式。所提出的新架構可犧牲極少量時間延遲而大幅度的減少所佔面積資源。

※ 1. 每項研發成果請填寫一式二份，一份隨成果報告送繳本會，一份送　貴單位研發成果推廣單位（如技術移轉中心）。

※ **2. 本項研發成果若尚未申請專利，請勿揭露可申請專利之主要內容。**

※ 3. 本表若不敷使用，請自行影印使用。

國科會補助計畫衍生研發成果推廣資料表

日期:2011/10/31

國科會補助計畫	計畫名稱: 子計畫三：針對三維規則型邏輯結構之架構探索及穩健合成系統開發(2/2)		
	計畫主持人: 黃俊達		
	計畫編號: 99-2220-E-009-037- 學門領域: 晶片科技計畫--整合型學術研究計畫		
研發成果名稱	(中文) 為取得面積與延遲間較佳平衡之三維可程式邏輯閘陣列架構探索		
	(英文) Architectural Exploration of 3D FPGAs towards a Better Balance between Area and Delay		
成果歸屬機構	國立交通大學	發明人(創作人)	黃俊達,陳嘉怡,李寶鑑
技術說明	(中文) 將標準的二維可程式邏輯閘陣列(2D FPGAs)使用同樣的方式，將訊號切換模式從二維的架構拓展至三維，而構成三維可程式邏輯閘陣列(3D FPGAs)架構。並藉由適當調整三維切換箱的排列方式以及其內部直通矽穿孔的連接數目，可以犧牲極少量時間延遲而大幅度的減少所佔面積。		
	(英文) We propose a generic 2D FPGA architecture can evolve into a 3D one by extending its signal switching scheme from 2D to 3D. Furthermore, by conducting architectural explorations for 3D FPGAs, we greatly reduce the footprint with only minor delay increase by properly tailoring the structure and deployment strategy of 3D-SBs.		
產業別	電機及電子機械器材業		
技術/產品應用範圍	1. Electronic Design Automation (EDA) (EDA 產業) 2. Integrated Circuit Design (IC 設計產業)		
技術移轉可行性及預期效益	提出省面積的新架構，並針對同一架構內不同的直通矽穿孔擺放方式做一個完整評估，目的是為了找出在不同架構內面積與時間延遲間更具平衡的擺放方式。所提出的新架構可犧牲極少量時間延遲而大幅度的減少所佔面積資源。		

註：本項研發成果若尚未申請專利，請勿揭露可申請專利之主要內容。

99 年度專題研究計畫研究成果彙整表

計畫主持人：黃俊達	計畫編號：99-2220-E-009-037-
計畫名稱：針對 3D 整合之電子設計自動化技術開發--子計畫三：針對三維規則型邏輯結構之架構探索及穩健合成系統開發(2/2)	

成果項目			量化			單位	備註（質化說明：如數個計畫共同成果、成果列為該期刊之封面故事...等）
			實際已達成數（被接受或已發表）	預期總達成數(含實際已達成數)	本計畫實際貢獻百分比		
國內	論文著作	期刊論文	0	0	100%	篇	
		研究報告/技術報告	0	0	100%		
		研討會論文	0	0	100%		
		專書	0	0	100%		
	專利	申請中件數	1	1	100%	件	
		已獲得件數	2	2	100%		
	技術移轉	件數	0	0	100%	件	
		權利金	0	0	100%	千元	
	參與計畫人力（本國籍）	碩士生	7	7	100%	人次	
		博士生	3	3	100%		
		博士後研究員	0	0	100%		
		專任助理	0	0	100%		
國外	論文著作	期刊論文	0	0	100%	篇	
		研究報告/技術報告	0	0	100%		
		研討會論文	5	5	100%		
		專書	0	0	100%	章/本	
	專利	申請中件數	1	1	100%	件	
		已獲得件數	1	1	100%		
	技術移轉	件數	0	0	100%	件	
		權利金	0	0	100%	千元	
	參與計畫人力（外國籍）	碩士生	0	0	100%	人次	
		博士生	0	0	100%		
		博士後研究員	0	0	100%		
		專任助理	0	0	100%		

其他成果 (無法以量化表達之成果如辦理學術活動、獲得獎項、重要國際合作、研究成果國際影響力及其他協助產業技術發展之具體效益事項等，請以文字敘述填列。)	1. 100 年 4 月 於 IEEE International Symposium on VLSI Design, Automation, and Test 2011 國際會議 榮獲 Best Paper Candidate 論文名稱：Performance-Optimal Behavioral Synthesis with Degenerable Compound Functional Units 2. 100 年 6 月 參與教育部主辦之「九十九學年度大學校院積體電路電腦輔助設計(CAD)軟體製作競賽」 榮獲 定題組 佳作 作品名稱：3D IC Design Partitioning with Power Consideration 3. 100 年 7 月 於 IEEE Computer Society Annual Symposium on VLSI 2011 國際會議 榮獲 Best Paper Award 論文名稱：Layer-Aware Design Partitioning for Vertical Interconnect Minimization

	成果項目	量化	名稱或內容性質簡述
科教處計畫加填項目	測驗工具(含質性與量性)	0	
	課程/模組	0	
	電腦及網路系統或工具	0	
	教材	0	
	舉辦之活動/競賽	0	
	研討會/工作坊	0	
	電子報、網站	0	
	計畫成果推廣之參與（閱聽）人數	0	

國科會補助專題研究計畫成果報告自評表

請就研究內容與原計畫相符程度、達成預期目標情況、研究成果之學術或應用價值（簡要敘述成果所代表之意義、價值、影響或進一步發展之可能性）、是否適合在學術期刊發表或申請專利、主要發現或其他有關價值等，作一綜合評估。

1. 請就研究內容與原計畫相符程度、達成預期目標情況作一綜合評估

■達成目標

□未達成目標（請說明，以 100 字為限）

□實驗失敗

□因故實驗中斷

□其他原因

說明：

2. 研究成果在學術期刊發表或申請專利等情形：

論文：■已發表 □未發表之文稿 □撰寫中 □無

專利：■已獲得 □申請中 □無

技轉：□已技轉 □洽談中 ■無

其他：(以 100 字為限)

3. 請依學術成就、技術創新、社會影響等方面，評估研究成果之學術或應用價值（簡要敘述成果所代表之意義、價值、影響或進一步發展之可能性）(以 500 字為限)

在本計畫中所提出的設計分割演算法能夠幫助設計三維電路時能具有較低的使用面積，這項優點能夠協助在 IC 設計領域在推進至三維製程時有極大的助益。不管是針對特定用途而設計的特殊應用積體電路(ASIC)或是規則型架構的電路，都可以減少面積以及資源上的損失並且提高生產良率及可靠度。而再針對三維規則型架構方面，針對同一架構內不同的直通矽穿孔擺放方式做一個完整評估，目的是為了找出在不同架構內面積與時間延遲間更具平衡的擺放方式。此架構探索流程能夠在尚未進行量產的三維架構上進行較完整的分析及探討，並在最後提出的新架構，使得在犧性極少量時間延遲下大幅度的減少所佔面積資源，有助於降低製造時耗費的硬體成本。